



## 18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

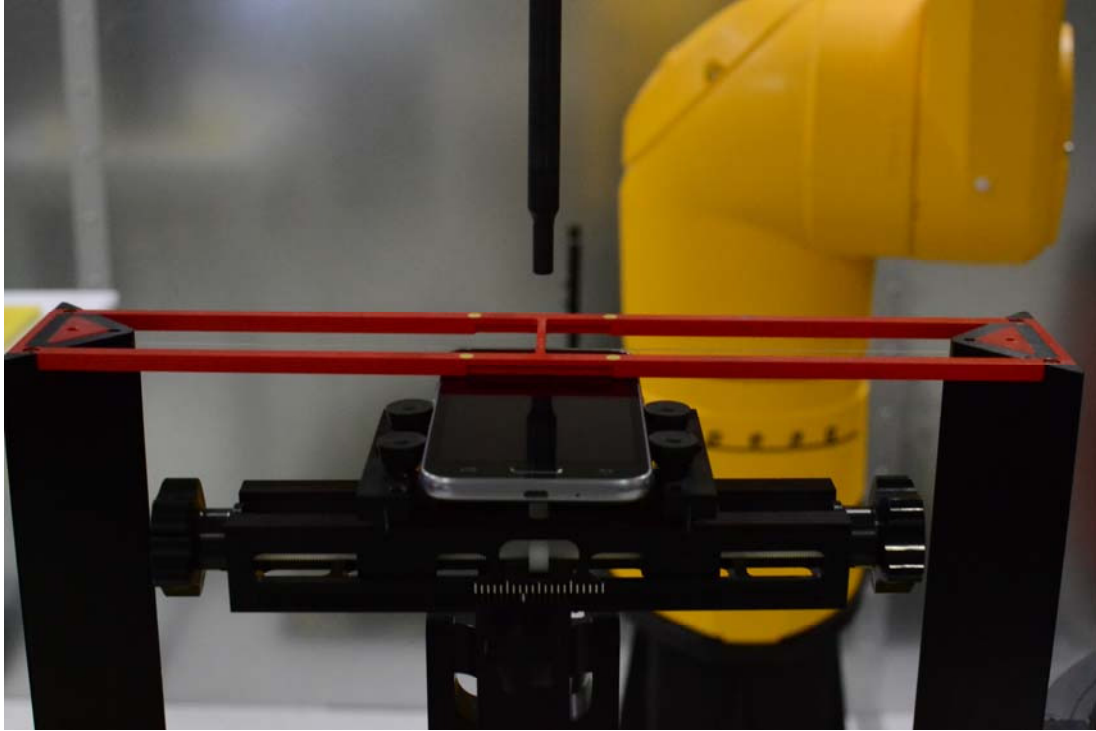
<b>FCC ID:</b> A3LSMJ120P	 <b>PCTEST</b> ENGINEERING LABORATORY, INC.	<b>HAC (RF EMISSIONS) TEST REPORT</b>		<b>Reviewed by:</b> Quality Manager
<b>Filename:</b> 0Y1602150341-R1.A3L	<b>Test Dates:</b> 02/22/2016	<b>EUT Type:</b> Portable Handset	Page 58 of 60	

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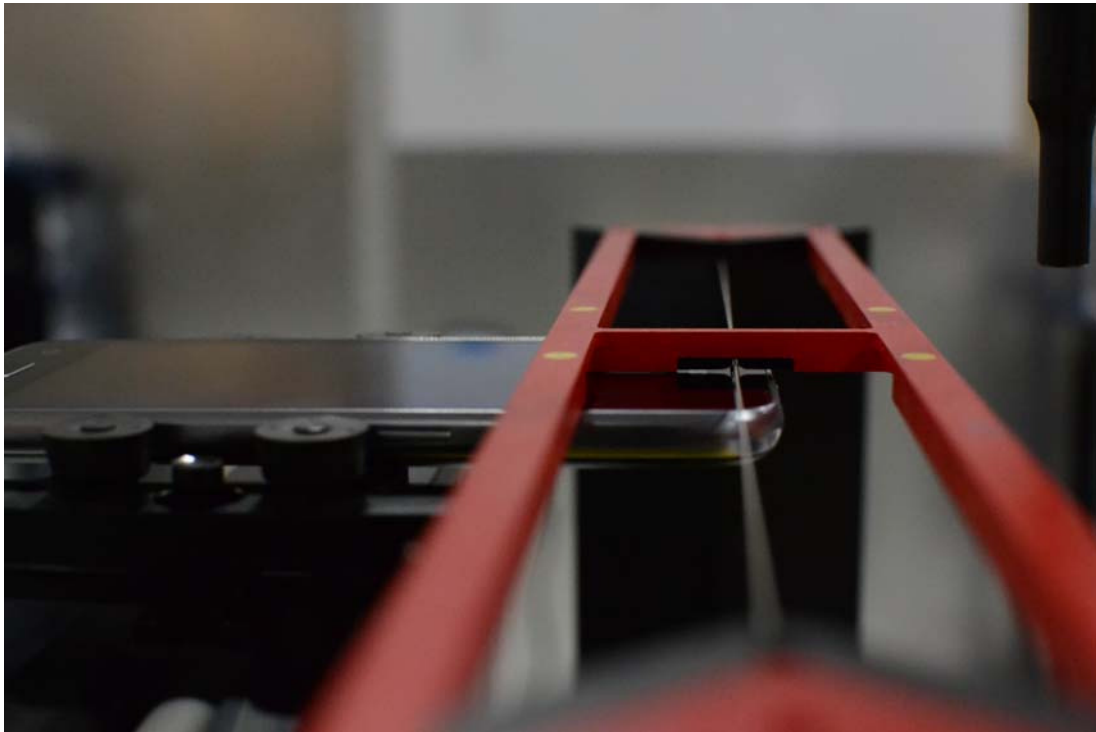
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**Figure 18-1**  
**Ear Reference Point HAC Phantom Alignment**



**Figure 18-2**  
**HAC Phantom Plane Alignment**

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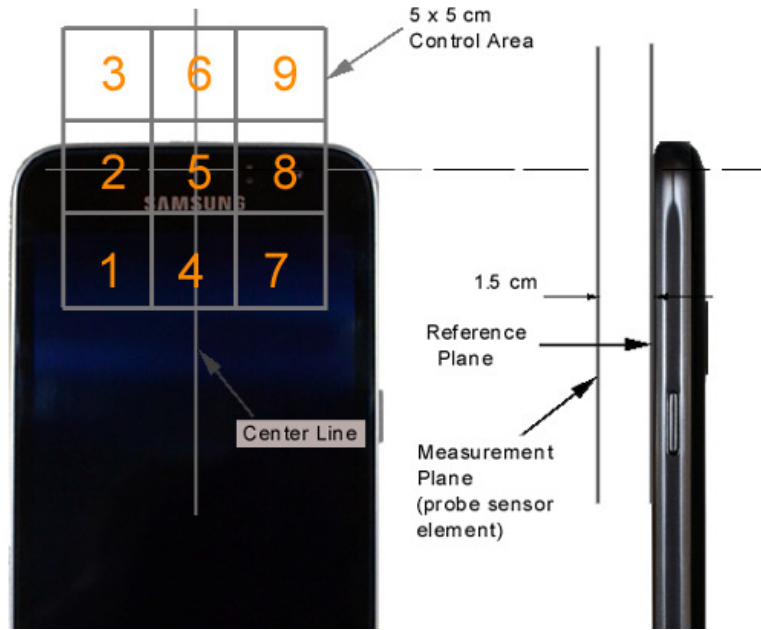


Figure 18-3 5x5 Scan grid above WD

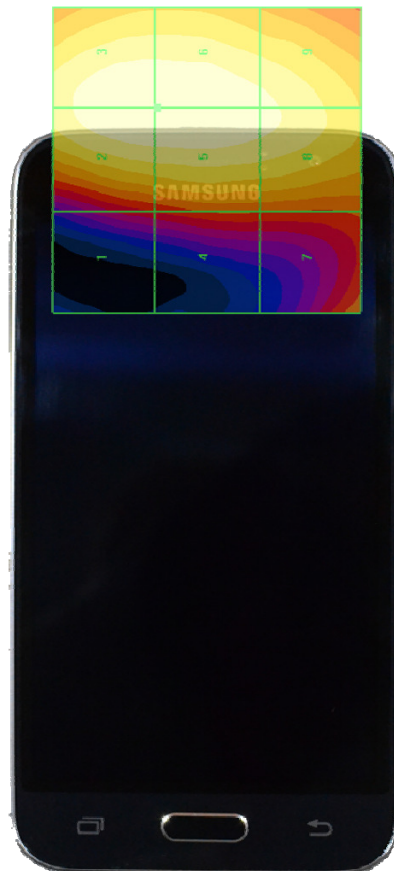




Figure 18-4 E-Field WD Scan overlay

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